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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

Pierre H. Woerlee

Examiner:

Monica D. Harrison

Gert Hooft

14084749082

Jisk Holleman

Serial No.:

10/534,385

Group Art Unit:

2813

Filed:

May 6, 20050

Docket No.:

NL02 1147 US

Title:

SILICON LIGHT EMITTING DIODE

Declaration Under 37 C.F.R. § 1.131

I, Jisk Hollcman, hereby present the following declarations.

Before September 19, 2002, while working with others (Pierre Woerlee and Gert Hooft being employed at Koninklijke Philips Electronics N.V. and I being employed at the University of Twente but working in cooperation with Koninklijke Philips Electronics N.V.):

1. I, along with Pietre Woerlee and Gert Hooft, invented and designed the structure and method as claimed in the above identified patent application. The invention included a structure and method for creating a radiation-crnitting semiconductor device that includes a semiconductor body and a substrate, which silicon-containing semiconductor device has a lateral semiconductor diode which is situated on an insulating layer that separates the diode from the substrate. The lateral semiconductor diode successively comprises a first semiconductor region of a first conductivity type and with a first doping concentration, a second semiconductor region of the first or a second conductivity type opposite to the first conductivity type and with a second doping concentration that is lower than the first doping concentration, and a third semiconductor region of the second conductivity type and with a third doping concentration that is higher than the second doping concentration, the first and the third semiconductor region each being provided with a connection region. During operation, radiation is generated in the second semiconductor region as a result of recombination of charge carriers injected from the first and

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the third semiconductor region in the second semiconductor region, wherein the second semiconductor region comprises a central portion that is surrounded by a further portion the bandgap of which is larger than that of the central portion.

- 2. I, along with the other inventors, prepared a six-page invention disclosure statement, a true and accurate copy of which is attached hereto as an Exhibit, with pertinent dates intentionally blocked out (each date preceding September 19, 2002) and certain confidential information blacked out and marked "CONFIDENTIAL." The Embodiment of the Invention section on page 4 and accompanying figures of the Exhibit provide further details as to the extent of our invention. The work described above and shown in the Exhibit was performed in the Netherlands. This invention disclosure statement provides details of the efficient light emitting device (LED) in silicon technology that I assisted in inventing and designing.
- 3. This invention disclosure statement was submitted to the Intellectual Property & Standards Division (formerly known as Corporate Intellectual Property) of Koninklijke Philips Electronics N.V. on February 25, 2002 (before the date of September 19, 2002), and was subsequently used in the preparation of the above-referenced patent application, which was first filed on November 7, 2002 as a European provisional patent application. This patent application entered the United States Patent and Trademark Office as a national stage patent application on May 6, 2005. Diligence was exercised by me, the other inventors, and the Intellectual Property & Standards Division in the searching, drafting, reviewing, and filing of the patent application in the time period between February 25, 2002, and the filing date of November 7, 2002.

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patent issued thereon.

Signed this 25 day of October 2006 by:

Jisk Molleman

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Embodiment of the invention

An overview a lateral stripe diode fabricated on SOI is presented in figure 2. The left contact (on highly n-doped silicon) injects electrons in the neutral region. The right contact is heavily p-doped silicon, from here holes are injected in the neutral region. In the neutral region electrons and holes recombine, and light emission occurs. The efficiency is increased by the e-h-confinement (see fig 2.). The material quality of SOI and its interfaces is excellent (there is a large effort to improve SOI quality for microprocessor fabrication). Hence the non-radiative recombination rate should be

An embodiment of the invention is described below. Standard thin-film SOI (Smart-Cut or SIMOX) with Si thickness around 150 mm and buried oxide thickness around 300 nm is used in the device fabrication (fig 3a). In the first step the device isolation (for example shallow trench isolation (STI) is performed (fig 3b). This is needed to have full dielectric isolation. Furthermore STI is necessary anyhow when CMOS devices are processed with the Si-LED. Then ultra-thin film SOI ($T_{\rm H} < 10$ nm) needs to be fabricated to confine the carriers by bandgap engineering. This can be done either by two anisotropic etching or by two LGCOS like oxidation steps (figure 3c, 3d). The latter procedure is preferred because it is a more robust process for forming of ultra-thin SOI (the oxidation is almost self limiting). Thereafter the n+ and p+ contact areas (3e) are formed by ion implantation (the source/drain implantations of the CMOS technology could be used). The process ends by a standard metallisation (fig. 1).

The fields of application of the invention.						
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References

- [1] L. Pavesi et al., Nature 408, pp 440 (2000).
- [2] W.L. Ng et al., Nature 410, 192-194 (2001).
- [3] M.A. Green et al., Nature 412, 805 (2001).

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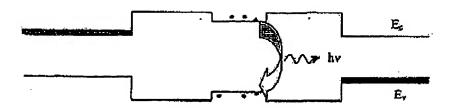


Figure 1: Shematic drawing of band diagram of lateral Si-LED

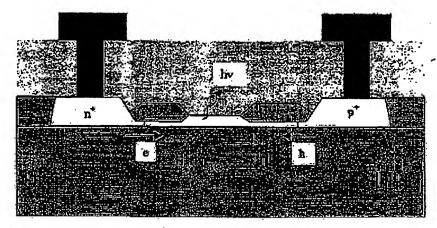
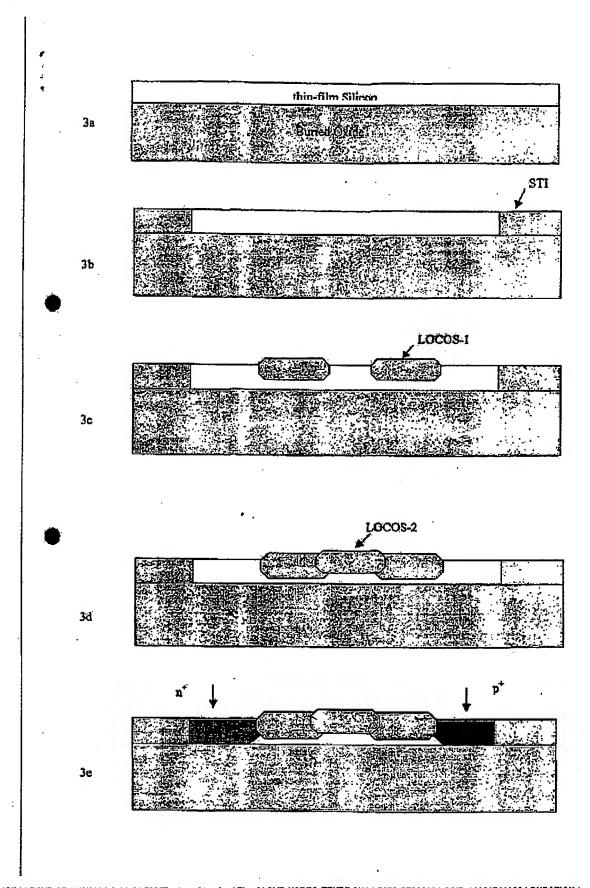


Figure 2: Schematic drawing of SOI-LED



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